

\*\*\*\*\* RECONNECTED TO STN INTERNATIONAL \*\*\*\*\*  
SESSION RESUMED IN FILE 'HOME' AT 07:47:37 ON 25 JUL 2003  
FILE 'HOME' ENTERED AT 07:47:37 ON 25 JUL 2003  
COST IN U.S. DOLLARS

	SINCE FILE ENTRY	TOTAL SESSION
FULL ESTIMATED COST	0.21	0.21

=> file inspect  
COST IN U.S. DOLLARS

	SINCE FILE ENTRY	TOTAL SESSION
FULL ESTIMATED COST	0.21	0.21

FILE 'INSPEC' ENTERED AT 07:47:52 ON 25 JUL 2003  
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FILE LAST UPDATED: 21 JUL 2003 <20030721/UP>  
FILE COVERS 1969 TO DATE.

<<< SIMULTANEOUS LEFT AND RIGHT TRUNCATION AVAILABLE IN  
THE BASIC INDEX >>>

=> s radiation hardening  
373465 RADIATION  
37653 HARDENING  
L1 4600 RADIATION HARDENING  
(RADIATION (W) HARDENING)

=> s deuterium  
L2 22893 DEUTERIUM

=> s vacuum anneal  
112377 VACUUM  
8131 ANNEAL  
L3 97 VACUUM ANNEAL  
(VACUUM (W) ANNEAL)

=> s l1 and l2 and l3  
L4 0 L1 AND L2 AND L3

=> s l2 and l3  
L5 1 L2 AND L3

=> d l5

L5 ANSWER 1 OF 1 INSPEC (C) 2003 IEE on STN

Full Text	References
AN 1986:2651524 INSPEC DN A86052230; B86026886	
TI Hydrogen in low-pressure chemical-vapor-deposited silicon (oxy)nitride films.	
AU Habraken, F.H.P.M.; Tijhaar, R.H.G.; van der Weg, W.F. (Dept. of Tech. Phys., Utrecht State Univ., Netherlands); Kuiper, A.E.T.; Willemsen, M.F.C.	
SO Journal of Applied Physics (15 Jan. 1986) vol.59, no.2, p.447-53. 30 refs. Price: CCCC 0021-8979/86/020447-07\$02.40 CODEN: JAPIAU ISSN: 0021-8979	
DT Journal	
TC Experimental	
CY United States	
LA English	

AN 1986:2651524 INSPEC DN A86052230; B86026886  
TI Hydrogen in low-pressure chemical-vapor-deposited silicon (oxy)nitride films.  
AU Habraken, F.H.P.M.; Tijhaar, R.H.G.; van der Weg, W.F. (Dept. of Tech. Phys., Utrecht State Univ., Netherlands); Kuiper, A.E.T.; Willemsen, M.F.C.  
SO Journal of Applied Physics (15 Jan. 1986) vol.59, no.2, p.447-53. 30 refs. Price: CCCC 0021-8979/86/020447-07\$02.40 CODEN: JAPIAU ISSN: 0021-8979  
DT Journal  
TC Experimental  
CY United States  
LA English

=> s l1 and l3  
L6 0 L1 AND L3

=> s 11 and 12  
L7 7 L1 AND L2

=> d 17 1-7

L7 ANSWER 1 OF 7 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2003:7671134 INSPEC DN A2003-15-4281-021; B2003-08-4125-038  
 TI Radiation-induced absorption in optical fibers in the near-infrared region: the effect of H2- and D2-loading.  
 AU Zabezhailov, M.O.; Tomashuk, A.L.; Nikolin, I.V.; Golant, K.M. (Fiber Opt. Res. Center, Moscow, Russia)  
 SO RADECS 2001. 2001 6th European Conference on Radiation and Its Effects on Components and Systems (Cat. No.01TH8605)  
 Piscataway, NJ, USA: IEEE, 2002. p.192-4 of xviii+504 pp. 10 refs. Also available on CD-ROM in PDF format  
 Conference: Grenoble, France, 10-14 Sept 2001  
 Price: CCCC 0-7803-7313-8/01/\$17.00  
 ISBN: 0-7803-7313-8  
 DT Conference Article  
 TC Experimental  
 CY United States  
 LA English

L7 ANSWER 2 OF 7 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2003:7671126 INSPEC DN A2003-15-4281-020; B2003-08-4125-035  
 TI **Radiation hardening** of pure silica optical fibres by high pressure hydrogen treatment.  
 AU Henschel, H.; Kohn, O.; Weinand, U. (Fraunhofer-INT, Euskirchen, Germany)  
 SO RADECS 2001. 2001 6th European Conference on Radiation and Its Effects on Components and Systems (Cat. No.01TH8605)  
 Piscataway, NJ, USA: IEEE, 2002. p.141-9 of xviii+504 pp. 10 refs. Also available on CD-ROM in PDF format  
 Conference: Grenoble, France, 10-14 Sept 2001  
 Price: CCCC 0-7803-7313-8/01/\$17.00  
 ISBN: 0-7803-7313-8  
 DT Conference Article  
 TC Experimental  
 CY United States  
 LA English

L7 ANSWER 3 OF 7 INSPEC (C) 2003 IEE on STN

Full Text	Cited References
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AN 2002:7428896 INSPEC DN A2002-23-4281-038; B2002-12-4125-043  
 TI **Radiation hardening** of pure silica optical fibers by high-pressure hydrogen treatment.  
 AU Henschel, H.; Kohn, O.; Weinand, U. (Fraunhofer-INT, Euskirchen, Germany)  
 SO IEEE Transactions on Nuclear Science (June 2002) vol.49, no.3, pt.3, p.1401-9. 10 refs.  
 Doc. No.: S0018-9499(02)05820-3  
 Published by: IEEE  
 Price: CCCC 0018-9499/02/\$17.00  
 CODEN: IETNAE ISSN: 0018-9499  
 SICI: 0018-9499(200206)49:3:3L:1401:RHPS;1-J  
 Conference: Sixth European Conference on Radiation and its Effects on Components and Systems (RADECS). Grenoble, France, 10-14 Sept 2001  
 DT Conference Article; Journal  
 TC Practical; Experimental  
 CY United States

LA English

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Full Text	Citing References
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AN 1990:3692772 INSPEC DN A90109266  
 TI Materials development for fusion reactors.  
 AU English, C.A.; Mazey, D.J. (AEA Technol., Harwell Lab., UK)  
 SO Nuclear Energy (Feb. 1990) vol.29, no.1, p.67-80. 58 refs.  
 Price: CCCC 0140-4067/90/\$4.00  
 CODEN: NUEGAH ISSN: 0140-4067  
 DT Journal  
 TC Bibliography; Practical; Experimental  
 CY United Kingdom  
 LA English

L7 ANSWER 5 OF 7 INSPEC (C) 2003 IEE on STN

Full Text	Citing References
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AN 1990:3582824 INSPEC DN B90021893  
 TI The effect of hydrogen on hot carrier and radiation immunity of MOS devices.  
 AU Nissan-Cohen, Y. (Gen. Electr. Corp. Res. & Dev., Schenectady, NY, USA)  
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 Price: CCCC 0169-4332/89/\$03.50  
 CODEN: ASUSEE ISSN: 0169-4332  
 Conference: Sixth International Conference on Insulating Films on Semiconductors INFOS'89. Garching, West Germany, 29-31 March 1989  
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 TC Experimental  
 CY Netherlands  
 LA English

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Full Text	Citing References
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AN 1987:2932109 INSPEC DN A87082844; B87046546  
 TI Photobleaching effect of radiation resistant image fibers.  
 AU Hayashi, S.; Wada, Y.; Chigusa, Y.; Fujiwara, K.; Hattori, Y. (Div. of Eng. Technol. Dev., Tokai Works, Sumitomo Electr. Ind. Ltd., Ibaraki, Japan)  
 SO Sumitomo Electric Technical Review (Jan. 1987) no.26, p.77-81. 1 refs.  
 CODEN: SETRAY ISSN: 0376-1207  
 DT Journal  
 TC Experimental  
 CY Japan  
 LA English

L7 ANSWER 7 OF 7 INSPEC (C) 2003 IEE on STN

Full Text	Citing References
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AN 1984:2345352 INSPEC DN A84111849  
 TI Critical issues in **radiation hardening** of fusion diagnostic systems.  
 AU Baur, J.F.; Barker, R.A.; Engholm, B.A.; Miller, P.H. (GA Technol. Inc., San Diego, CA, USA)  
 SO 10th Symposium on Fusion Engineering Proceedings (Cat. No. 83CH1916-6 NPS) New York, NY, USA: IEEE, 1983. p.411 vol.1 of 2 vol. xxiv+2158 pp.  
 Conference: Philadelphia, PA, USA, 5-9 Dec 1983  
 Sponsor(s): IEEE; Princeton Plasma Phys. Lab.; US DOE; EPRI; ANS  
 DT Conference Article  
 TC Practical  
 CY United States  
 LA English

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